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J1046 U.S. PTO
09/942213

	Subclass	ISSUE CLASSIFICATION
	Class	

PATENT NUMBER

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U.S. UTILITY Patent Application

O.I.P.E.	PATENT DATE
 SCANNED AC 21 Q.A. 	

APPLICATION NO. 09/942213	CONT/PRIOR F	CLASS 438 382	SUBCLASS 145	ART UNIT 2812 227	EXAMINER J Strega
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APPLICANTS

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2.625

Method and apparatus for inspecting a semiconductor device

TIME

PTO-2040
12/89

ISSUING CLASSIFICATION

□ TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.				NOTICE OF ALLOWANCE MAILED	
	_____ (Assistant Examiner) _____ (Date)				
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____				ISSUE FEE	
	_____ (Primary Examiner) _____ (Date)			Amount Due	Date Paid
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.				ISSUE BATCH NUMBER	
	_____ (Legal Instruments Examiner) _____ (Date)				

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